



BACnet® TESTING LABORATORIES

TESTING GUIDE

Revision 26

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1 Introduction

The *BTL Testing Guide* provides a generalized testing process for the application of the BTL test suite on an IUT. This guide is intended to help in the preparation of a BACnet device for official BTL testing and/or to improve the in-house testing of BACnet devices.

Before proceeding with this guide's testing procedures, the *Getting Started Guide* should be read. To get the most out of the *BTL Testing Guide* a general understanding of the documents in the BTL Documentation Package should be acquired.

The *BTL Testing Guide* is written for the Test Planner and Tester, which are defined below.

1.1 Test Planner

The Test Planner is the individual that will identify the testable IUT functionality, prepare the IUT's configuration, determine the tests to apply, and select appropriate parameters for those tests. The Test Planner uses the BTL test package to create a custom test plan for the IUT that will be used by the Tester. The Test Planner requires a thorough understanding of the functionality of the IUT and how to make the IUT exhibit all claimed functionality. All information the Test Planner needs to accomplish the task is contained in following sections of this guide or within the documents referenced by this guide.

The Test Planner will generate a document, spreadsheet or some means of recording notes and parameters for each selected test. This can then be used by the Tester to record results. From here forward this section will be referred to as the 'Notes & Results' section.

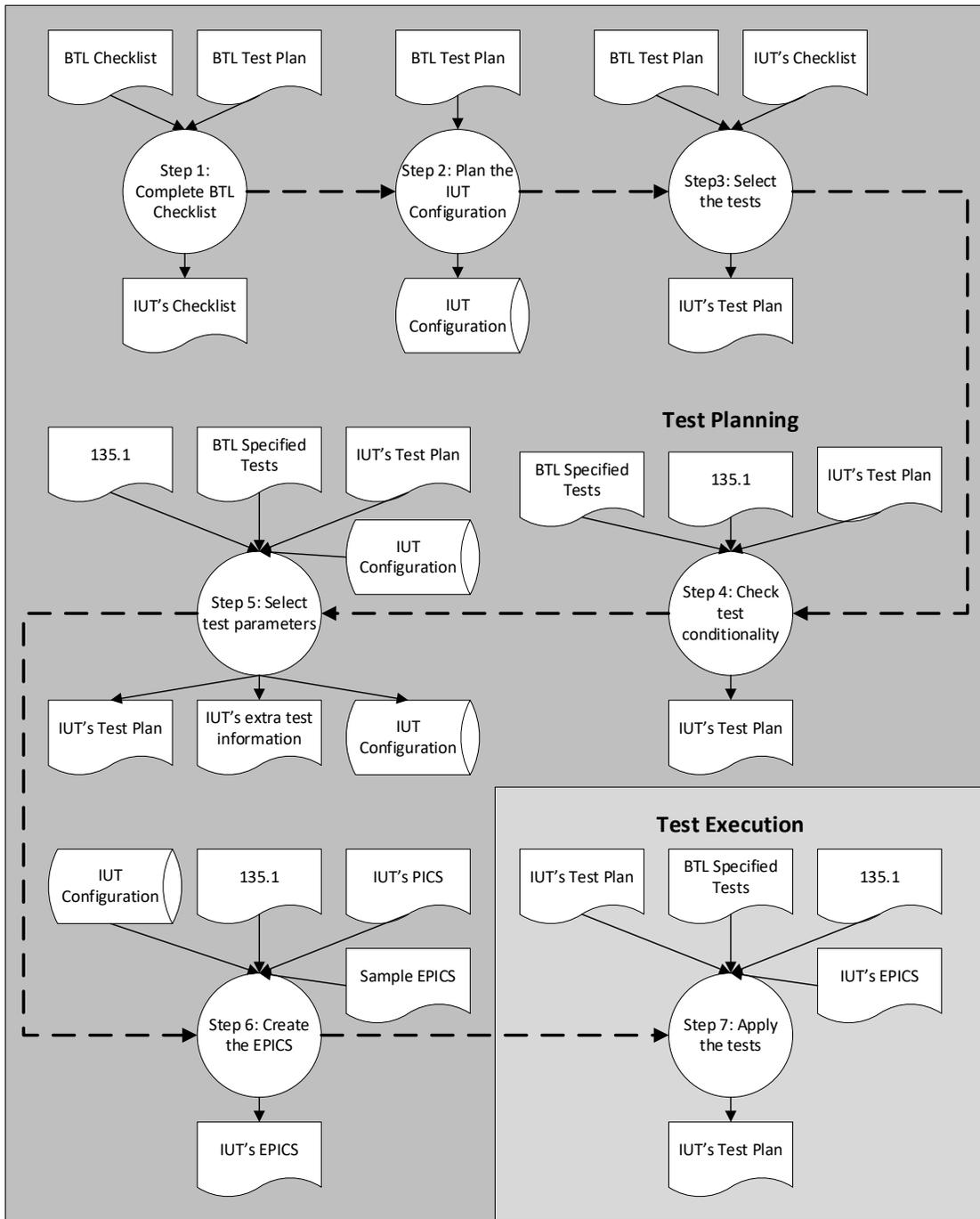
1.2 Tester

The Tester is the individual that applies the test plan developed by the Test Planner to the IUT. The Tester will use test tools to execute the tests. The Tester requires a thorough understanding of the configuration of the IUT, and the test tools being used. The Tester will need to be able to understand the concepts used by tests. All information the Tester needs to accomplish this task is contained within the last step, or within the documents referenced by the last step, of this guide.

1.3 The Test Process

The testing process is divided into two phases: test planning and test execution. The test planning phase produces the IUT's custom test plan. The test execution phase applies the IUT's custom test plan to the IUT.

Figure 1: The test planning and execution process.



2 Test Planning

The test planning phase produces the IUT's custom test plan.

2.1 Step 1 – Complete BTL Checklist

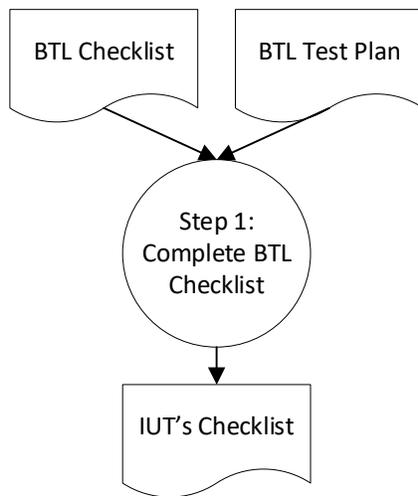
2.1.1 Purpose

The goal is to complete the **BTL Checklist** for the IUT. The **BTL Checklist** contains a table of BACnet functionality that may or may not apply to the IUT. The goal of this step is to understand the table and select the functionality within the table that is implemented by the IUT. The completed table identifies the IUT's capabilities that will, in turn, be mapped onto tests.

The BTL Checklist is the complete list of BACnet functionality implemented in the device. The BTL Checklist is not the list of BACnet functionalities the vendor wants tested.

The **BTL Checklist** document is filled out in this step by marking the items implemented by the IUT with an X.

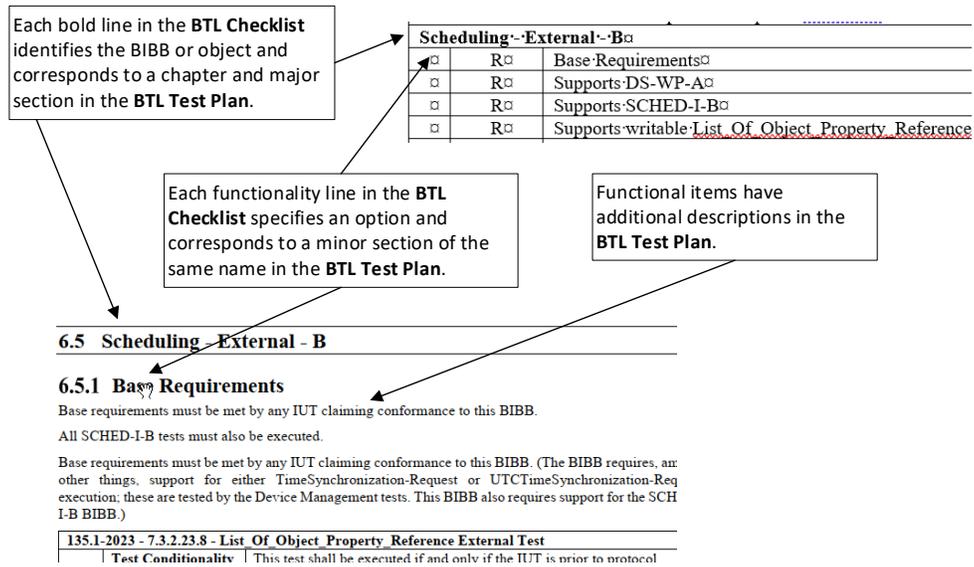
Figure 2: Complete Checklist step.



2.1.2 Requirements

The **BTL Checklist** document will be filled out during this step and is the main working document used during this step. The **BTL Test Plan** will be used as a reference document during this step. It contains enhanced descriptions of the items listed in the Checklist and will be used to better understand the items when necessary. The **IUT's PICS** may be useful as a reminder as to what functionality is implemented by the IUT.

Figure 3: Relationships between the *BTL Checklist* and the *BTL Test Plan* documents.



2.1.3 Completing the BTL Checklist

For information on the columns and codes in the *BTL Checklist*, refer to the document description at the start of the *BTL Checklist* document.

For each section in the *BTL Checklist*, determine whether the IUT implements the related functionality. Most sections in the *BTL Checklist* correspond either to a BIBB or an Object Type. If the IUT implements the BIBB or can contain objects of the specified type, place an X in the ‘Supports’ column for the Base Requirements row.

For each row in the section marked as supported, determine whether the IUT implements the functionality described by the row. If the description in the ‘Option’ column does not provide enough information to understand the functionality, refer to the corresponding section in the *BTL Test Plan* document for more information. If more information is needed to determine whether the IUT supports the functionality review the test definition in *ASHRAE 135.1* or *BTL Specified Tests*.

Certain aspects of BACnet imply the implementation of other aspects. For instance, a Calendar object could be something that the period field of an exception-schedule entry in a Schedule object might reference. For that reason, if a Calendar object is implemented, then it must be an implementation that is compliant with all the requirements of the behavior of a Calendar object which an exception-schedule in a Schedule object might reference. There is no tolerance for implementation of “a Calendar object that behaves like no one else’s”. All standard object types which appear in an implementation must adhere to the rules regarding that object type. All services which appear in an implementation must adhere to the rules regarding that service. All standard properties which appear in an implementation must adhere to the rules regarding the behavior of that property and the rules regarding the datatype and range of the value of that property. Non-compliance is not excused by not claiming the functionality. Any additional areas where the submitted device exhibits an implementation will have the standard specified requirements of that area tested. If the IUT implements the functionality, place an X in the ‘Supports’ column. An IUT which implements non-compliant functionality, will not pass by leaving a blank in the ‘Supports’ column (nor, if it is non-compliant, by placing an X in the ‘Supports’ column). You should though, place an X in the ‘Supports’ column if the IUT implements the functionality, even if it is currently non-compliant. In the end it will need to be claimed (or able to be claimed) to successfully pass the testing.

Figure 4: Part of a completed *BTL Checklist* document.

Support	Listing	Option
Basic BACnet Functionality (applies to all BACnet devices)		
X	R	Base Requirements
	C ¹	Uses static router address configuration
	C ¹	Uses Who-Is and I-Am services for router address
	C ¹	Uses Who-Is-Router-to-Network (any network) f
	C ¹	Uses Who-Is-Router-to-Network (specific network)
	C ¹	Uses MAC broadcasts for router discovery
¹ At least one of these options must be supported if the service requests other than COV notifications.		
Segmentation - Transmits Segmented Messages		
	R	Base Requirements
	C ¹	Transmits segmented requests
	C ²	Transmits segmented responses
¹ Required if the device is capable of sending a request ² Required if the device is capable of sending a response		
Segmentation - Receives Segmented Messages		
	R	Base Requirements
	C ¹	Processes received segmented responses
¹ Required if the device is capable of sending confirmed response APDU of more than 50 octets in length.		
Device Object		
X	R	Base Requirements
X	C ¹	Supports database revision properties
¹ This option must be supported if the device implements database revision properties.		
Analog Input Object		
X	R	Base Requirements
X	S	Supports writable Out_Of_Service properties
Analog Output Object		
X	R	Base Requirements
X	R	Supports command prioritization
X	S	Supports writable Out_Of_Service properties

This simple device does not support any address discovery.

This device does not support any segmentation options

This device is implemented to a newer version of BACnet and supports the database_revison property

This device supports Analog Input and Analog Output objects. In both objects, the device supports writable Out_Of_Service properties.

2.2 Step 2 – Plan the IUT Configuration

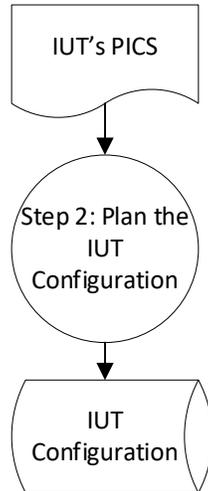
2.2.1 Purpose

Determine how the IUT should be configured to allow the tests to be executed.

In order for the BTL tests to be applied, the IUT must be configured to exhibit all of the claimed functionality. For example, the IUT will be required to contain at least one instance of each supported object type. The goal of this step is to design an IUT configuration that is capable of exhibiting all the IUT's claimed functionality. In some cases, multiple IUT Configurations will be required.

It is possible that the IUT Configuration(s) that is developed in this step may need to be modified when the tests parameters are selected in Step 5 – Select Test Parameters.

Figure 5: Plan the IUT Configuration step.



2.2.2 Requirements

To fill out the design of the IUT Configuration the Test Planner should have the completed *BTL Checklist* and the *IUT's PICS* on hand.

The *BTL Checklist* and the *IUT's PICS* will be used as references to ensure that the IUT Configuration exercises all the IUT's functionality.

2.2.3 Designing the IUT Configuration

For each functional item claimed in the completed *BTL Checklist*, determine the IUT setup required to exercise the functionality. The initial IUT Configuration that is designed in this step may be modified in later steps in this process as the test planning continues.

Note that there is no actual documented output from this step in the process. The IUT's configuration should be documented in whatever form the Test Planner is comfortable with. In the last step of the Test Planning phase, the IUT's configuration will be used to generate the *IUT's EPICS*. EPICS are not generated at this stage as they are generally difficult to generate and maintain and as such are not created until the final IUT Configuration is determined.

If there are two or more functional items that cannot coexist in the IUT at the same time, either multiple IUT Configurations must be provided, or multiple IUTs must be provided. For example, if the firmware supports both Analog and Binary output objects, but no model of the IUT supports both simultaneously, then multiple IUTs or IUT Configurations must be provided.

During this stage, the Test Planner will:

1. Identify all the object types supported by the IUT. Ensure that at least one instance of each object type is contained in the IUT's configuration. If the IUT supports multiple forms of an object type (each supporting a different set of properties), then the IUT's configuration should contain a sample of each form of the object type.
2. Provide property values that allow all conditionally writable properties to be writable. In some IUTs, certain properties will only be writable under specific conditions which are usually related to the values of other properties. The Test Planner should choose property values such that conditionally writable properties are writable, and such that the general functionality of the IUT is not hindered.
3. Review all the functional items supported by the IUT. If, for a specified functional item, the IUT must contain a type of object, or an object configured in a specific manner, then the IUT's configuration should be modified to contain such an object. For example, if the IUT supports alarming using Event Enrollment objects, an Event Enrollment object should be supplied for each Event-Type that the IUT supports.

4. Identify all the physical media that the IUT supports. Ensure that either the IUT is equipped with a network connection of each type, or that an instance of the product is available with a network connection of each type.

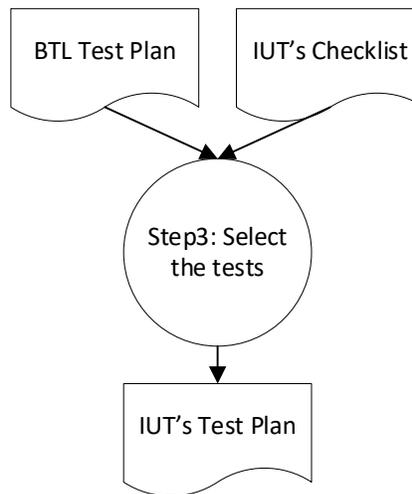
2.3 Step 3 – Select the Tests

2.3.1 Purpose

Test selection consists of identifying tests that will be applied to the IUT. During this step, the test planner will be creating an initial test plan for the IUT based on the **BTL Test Plan** document. This initial test plan will consist of all tests apply to the IUT.

The parameters for the tests will not be chosen in this step; test parameters are identified in *Step 5 – Select Test Parameters*.

Figure 6: Selects the Tests step.



2.3.2 Requirements

The **BTL Test Plan** is the template document that will be filled out during this step and is the main working document for this step. The completed **BTL Checklist** is used as a reference document to determine which entries in the **BTL Test Plan** need to be included in the **IUT's Test Plan**.

2.3.3 Selecting Tests

Create a copy of the **BTL Test Plan** document for the IUT. This copy will be referred to as the **IUT's Test Plan** to distinguish it from the original **BTL Test Plan** document. The **IUT's Test Plan** will be modified during the remainder of the Test Planning phase to become the custom test plan for the IUT.

For each section in the **IUT's Test Plan**, if the section is checked in the completed **BTL Checklist**, mark the section in the **IUT's Test Plan** document. The test plan section can be marked by placing an X in the first column, or the whole section can be highlighted. With highlighting, the selected sections will be easier to find when scanning in the document.

Figure 7: An example of marking a selected test.

X	BTL - 7.2.X1 - Date Pattern Properties Test	
	Test Conditionality	Must be executed.
	Test Directives	Apply to the Date_List property.
	Testing Hints	

Selected tests can be marked by placing an X in the first column.

The resulting document is the set of tests that apply to the IUT and will be referred to as the *IUT's Test Plan*.

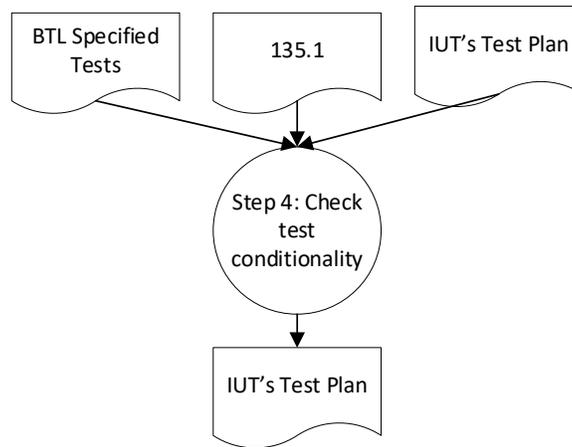
2.4 Step 4 – Check Test Conditionality

2.4.1 Purpose

To identify tests that cannot be applied to the IUT due to limitations in the test design, or in the IUT's configurability.

Some of the tests in the *BTL Test Plan* document have conditions under which the test should be skipped. These conditions are either described in the test definition, or within the test plan entry in the 'Test Conditionality' row. This step will identify the conditional tests and determine which will not need to be applied to the IUT.

Figure 8: Check Test Conditionality step.



2.4.2 Requirements

To evaluate the conditionality of tests the *IUT's Test Plan*, *BTL Specified Tests*, and *ASHRAE 135.1* will be required. The *IUT's Test Plan* will be modified during this step and is the main working document for this step. The *BTL Specified Tests* and *ASHRAE 135.1* are reference documents used during this step to detail the test steps and to further clarify test conditionality.

Figure 9: 'Test Conditionality' specifies the conditions under a which a test may be skipped.

<div style="border: 1px solid black; padding: 5px; width: fit-content;"> For some tests, the BTL identifies conditions under which the test may be skipped. The Test Conditionality field will note whether the BTL has identified such conditions. </div>	BTL - 7.3.2.23.6 - Weekly_Schedule Restoration Test	
	Test Conditionality	If it is impossible to configure the IUT in the manner specified by this test, the test shall be omitted.
	Test Directives	
	Testing Hints	

2.4.3 Evaluating Conditionality

In each test entry in the *BTL Test Plan* document, there is a ‘Test Conditionality’ field. This field indicates whether the test must always be executed against a device that supports the related functionality, or whether there are conditions under which it may be skipped. The conditions are either described in the ‘Test Conditionality’ field, or the field will refer to the test definition. The test definition will either be in *ASHRAE 135.1* or in the *BTL Specified Tests* document.

For each test in the *IUT’s Test Plan*, if there are conditions under which the test shall be skipped, review the conditions to determine if the conditions exist for the IUT. If the conditions exist, mark the test entry as ‘Skipped’. Otherwise, the test will be included in the set of tests that must be applied to the IUT.

If desired, the test parameter selection which is described by the next step, can be performed while test conditionality is evaluated.

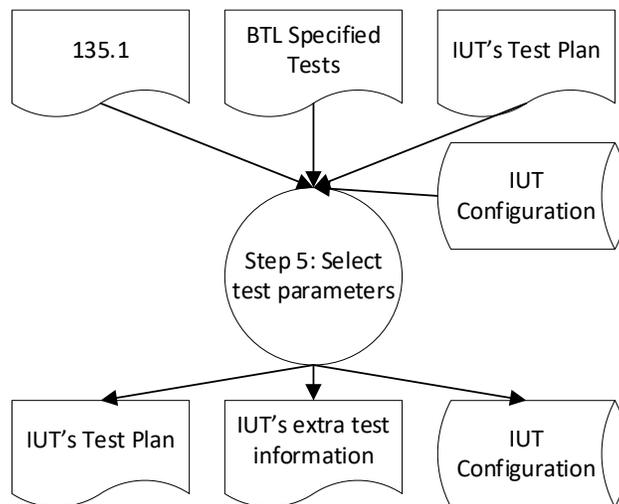
2.5 Step 5 – Select Test Parameters

2.5.1 Purpose

Determine the parameters for each test in the *IUT’s Test Plan* that will be applied to the IUT.

Most of the tests that will be applied to the IUT will be customized for the IUT. This customization is achieved through the appropriate selection of test parameters.

Figure 10: Select Test Parameters step.



2.5.2 Requirements

To select the parameters for the tests the following documents are needed: the *IUT’s Test Plan*, *ASHRAE 135.1*, *BTL Specified Tests*, and the IUT’s configuration.

Before proceeding with this step, review the section in the *Getting Started Guide* that discusses test parameter selection.

The *IUT’s Test Plan* will be used for recording the parameters selected for the tests and will be the main working document for this step.

The test definitions contained in the *BTL Specified Tests*, and *ASHRAE 135.1* documents will be used during this step to help in identifying and selecting test parameters.

The IUT’s configuration will be reviewed and modified during this test. It is from the IUT’s configuration that most parameters will be selected. In some cases, the IUT’s configuration will be insufficient as designed and may need to be modified to accommodate all selected tests.

While selecting the test parameters, the Test Planner will consider how to cause the IUT to exhibit the tested behaviour. The Test Planner should also consider the 'Test Directives' section of the test plan to determine if the BTL recommends running the test multiple times with different parameters. If the Tester will have to take any special actions during the test, these actions should be documented to assist the RBTO when they run the test.

2.5.3 Selecting Test Parameters

Almost all BTL tests will require that some parameters be selected.

Figure 10b: Example of Test Directives.

Test Directives will provide additional information when selecting parameters for the tests.

BTL - 7.2.4 - Date Pattern Properties Test	
Test Conditionality	If the IUT does not contain any calendars with a writable Date_List, this test shall be skipped.
Test Directives	Apply to the Date_List property.
Testing Hints	

These parameters will generally be objects, properties, new property values, etc and/or properties contained in the IUT. The parameters for a given test are defined and documented in the test definition for manual testing.

For manual testing, the parameters consist of all the items referred to in the test definition for which a specific value is not identified.

Figure 11: An example of a test parameter required for manual testing.

8.14.2 Array Properties

Purpose: To verify that the IUT can initiate an AddListElement service request that contains the 'Property Array Index' parameter.

Test Steps:

1. RECEIVE AddListElement-Request,
 - 'Object Identifier' = (any object that contains a property having a datatype that is an array of lists),
 - 'Property Identifier' = (any property having a datatype that is an array of lists),
 - 'Property Array Index' = (any value > 0),
 - 'List of Elements' = (one or more elements with the correct datatype to add to the list)
2. TRANSMIT BACnet-SimpleACK-PDU

These item is not specified by the test definition. As such they are parameters that the Test Planner must determine.

Apply the following steps to each selected test in the *IUT's Test Plan* (excluding those that that will be skipped as identified in the previous section).

1. Identify any configuration changes that must be made to the IUT in order to make the IUT exhibit the functionality being tested. If the changes are not of the type that would be represented in the IUT Configuration, document the steps that the Tester must take to assist the RBTO during BTL Testing.
2. Review the test definition to understand the test and its purpose.
3. Review the Test Directives and Testing Hints fields in the *IUT's Test Plan* for any information on selecting parameters for the test.
4. Select appropriate parameters and record them in the Notes & Results section. If the IUT Configuration does not contain values that would be appropriate, modify the IUT Configuration as required. If the IUT Configuration cannot be modified to support the test, another IUT Configuration may be required.

Figure 12: An example record of test parameters in the ‘Notes & Results’ section.

135.1 - 7.3.1.3 - Command Prioritization Test		
	Test Conditionality	Must be executed.
X	Test Directives	
	Testing Hints	
Notes & Results: Tested Object = Analog Object, 1 Vlow = 10 Vmed = 20 Vhigh = 30 Plow = 5 Pmed = 3 Phigh = 1		

5. If the testing requires multiple IUT Configurations, record the IUT Configuration to apply the test with in the ‘Notes & Results’ section.

If the IUT setup needs to be changed to make it exhibit the desired functionality, and those changes will not be supplied in an IUT Configuration provided to your selected RBTO, document the steps that the Tester must take.

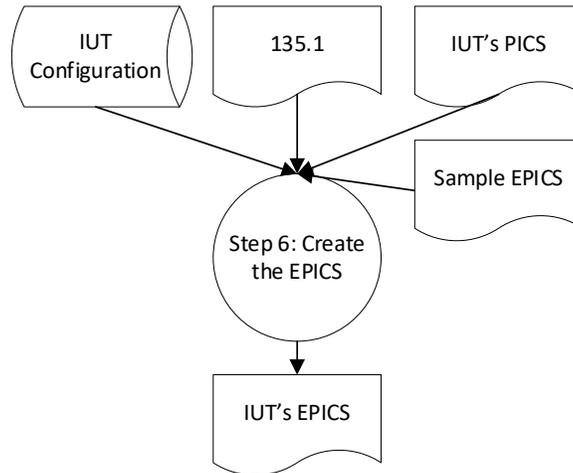
For more information on choosing test parameters, refer to section 4 **Test Parameter Selection Hints**.

2.6 Step 6 – Create the EPICS

2.6.1 Purpose

During this step, the Test Planner will generate an *EPICS* document for each of the IUT Configurations. The *IUT’s EPICS* will be used during the testing of the IUT in the next step *Step 7 – Apply the Tests*.

Figure 13: Create the EPICS step.



2.6.2 Requirements

The Tester will require all the completed IUT Configurations to generate the *IUT’s EPICS*. The *IUT’s PICS* already contains much of the same information as the *IUT’s EPICS*, so it may be useful as a reference when creating the *IUT’s EPICS*. The syntax and structure of an EPICS is defined in *ASHRAE 135.1*. The *exampleTestEpics.tpi* can be used as a reference document for syntax during this step.

2.6.3 Generating an EPICS

The *exampleTestEpics.tpi* is available from the BTL Manager, which can be modified to match the IUT. The Test Planner should create an EPICS for each of the IUT Configurations that have been generated. The EPICS must match the IUT Configuration exactly. If it does not match, then some of the tests will fail.

3 Test Execution

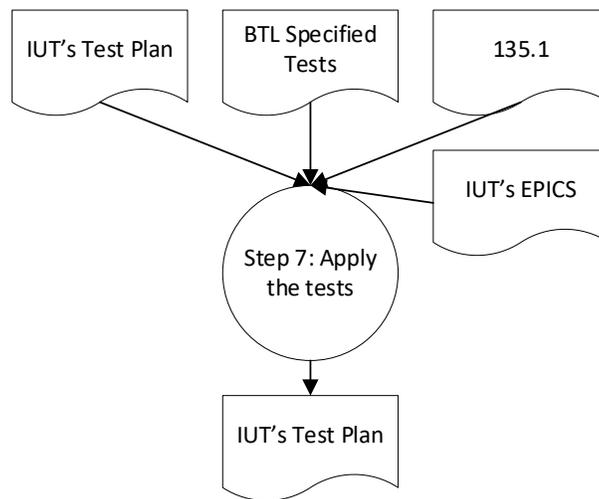
The test execution phase applies the IUT's custom test plan to the IUT.

3.1 Step 7 – Apply the Tests

3.1.1 Purpose

In this step the Tester will apply the tests identified in the *IUT's Test Plan* to the IUT, recording the results in the *IUT's Test Plan*.

Figure 14: Apply the Tests step.



3.1.2 Requirements

The Tester should ensure that the Test Planner provided the Tester with the *IUT's Test Plan*, all the IUT Configurations and each associated *IUT EPICS*, and the tools to change the IUT's configuration.

Before proceeding with this step, the *IUT's Test Plan* will have had the tests to apply selected and configured. For manual tests, the Tester will follow the steps laid out in the *BTL Manual Test Instructions* document.

The Tester should expect that some of the test definitions will be referred to during the testing and as such should have *ASHRAE 135.1* and *BTL Specified Tests* available as reference documents.

The main working document during this step is the *IUT's Test Plan* which not only identifies the tests to be applied but is also used as a repository for the test results.

Before proceeding with this step, the Tester should have a reasonable understanding of the test tools that will be required.

3.1.3 Executing Tests

The *IUT's Test Plan* will indicate all the tests that apply to the IUT. Each entry in the test plan that applies to the IUT will be marked with an *X*. If a test that applies to the IUT should not be executed, the Test Planner will have noted this in the 'Notes & Results'.

Figure 15: An example of an automated test that the Test Planner decided should be run manually.

Even though this test applies to the IUT, the Test Planner has determined that applying this test will be cumbersome. The test Planner has instructed the Tester to skip this test and execute the alternate in its places (as allowed by the Test Conditionality field).

135.1 - 7.2.2 Write Support Test Procedure		
X	Test Conditionality	For each property on which 9.22.1.X2 is executed on each writable datatype, that property can be skipped in the performance of 7.2.2. To satisfy this test item, test 7.2.2, need only be executed using WriteProperty.
	Test Directives	None.
	Testing Hints	
Notes & Results: Due to the number of writable properties in this IUT, this shall be skipped and 9.22.1.X2 shall be executed. See test plan entry for 9.22.1.X2.		

Before executing any of the tests, the Tester should determine if the Test Planner developed multiple IUT Configurations. If there are multiple IUT Configurations, then the Tester may decide to determine the order in which to apply the tests based on the IUT Configuration used by each test.

1. Read the test plan entry. Evaluate and understand all the fields.
2. Review the test definition in *ASHRAE 135.1* or *BTL Specified Tests*.

Figure 16: Identifying the location of a test plan entry’s test definition.

This field identifies the test. The test definition can either be found in 135.1 or the BTL Specified Tests document. This field will indicate which document the definition is located in.

135.1 - 7.2.2 Write Support Test Procedure		
X	Test Conditionality	For each property on which 9.22.1.X2 is executed on each writable datatype, that property can be skipped in the performance of 7.2.2. To satisfy this test item, test 7.2.2, need only be executed using WriteProperty.
	Test Directives	None.
	Testing Hints	

3. Record the time and date that the test was executed.
4. Record the result of the test in the ‘Notes & Results’ field. Indicate a Pass or Fail by placing a P or F under the X in front of the ‘Notes & Results’.
5. If the IUT failed the test, indicate the step in the test definition that failed, and how the IUT failed the test step.
6. Regardless of whether the IUT passed or failed the test, record any interesting information such as, “the IUT took longer than usual to process the request to respond during step 6”, or “the IUT generated a number of unrelated ReadProperty-Requests after step 3”.

4 Test Parameter Selection Hints

This section discusses how to select test parameters to maximize the probability of finding defects in the IUT. The purpose of pre-testing a BACnet product is to increase the probability that the IUT will pass tests when applied by the RBTO. Good parameter selection during pre-testing is important to realize this goal. Keep in mind that the RBTO's tester will be trying to find interoperability issues in your device, so they are likely to choose parameter values that will stretch the limits of your device.

1. Some tests will provide more benefit if they are executed multiple times with varying parameters. The pre-test package is developed such that each test is executed once, but the Test Planner can always choose to have a test applied two or more times. If this is the case, the Test Planner should provide multiple sets of parameters in the 'Notes & Results' field of the test plan entry.
2. When selecting parameter values, try not to select the normal values that would be encountered. Odds are that those values have already been tested and work. Try values at each end of the valid value range, such as the minimum and maximum values.
3. Negative tests are those that ensure that the IUT responds correctly to invalid requests, such as invalid parameter values. History has shown that these tests commonly fail. Repeating these tests with a variety of unexpected parameters may reveal issues. Use your imagination!
4. Tests that stretch the limit of internal buffers are also known to result in numerous issues. If the test allows for a selection of data values that will significantly increase the size of the request, or the response, the Test Planner should attempt to choose values that do so. An example would be to choose character string values that are very long when writing to character string properties.

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Version	Date	Author	Change
0.17	12-Oct-2004	Bill Swan	• Severe Problem Resolution Procedure
0.18	19-Oct-2004	Bill Swan	• Updated Severe Problem Resolution Procedure
0.19	25-Jan-2005	Carl Neilson	• Fixed typos
0.20	02-Feb-2005	Carl Neilson	• Formatted new text.
0.21	11-Jul-2005	Jim Butler	• Added section on test reporting and statistics
0.22	26-Oct-2005	Jim Butler	• Added section on bug tracking and reporting
0.23	05-Apr-2006	Duffy O'Craven	• Added language on unclaimed functionality
0.24	03-May-2006	Duffy O'Craven	• Testing unclaimed but testable functionality
0.25	08-May-2006	Duffy O'Craven	• Testing unclaimed functionality with a suite
0.26	21-Jun-2006	Duffy O'Craven	• Testing is always all function, not a subset
4.0.0	13-Sep-2006	Carl Neilson	• Changed revision numbering
4.0.1	28-Mar-2008	Lori Tribble	• Updated document with current procedures for review by BTL-WG.
4.0.2	22-May-2008	Lori Tribble	• Update document and marked sections that need further review.
4.0.3	15-Jul-2008	Lori Tribble	• Rejected changes in 4.0.2 and accepted changes from 4.0.1.
5.0.1	3-Nov-2008	Lori Tribble	• Removed section regarding BTL Lab reporting to BTL Working Group. This will go into a different document which is not part of the BTL Test Package.
5.0.3	26-Jun-2009	Lori Tribble	• Fixed spelling error on pg 9. Fixed broken link on page 13.
9.0.1	13-Oct-2011	Duffy O'Craven	• Updated from 5.0.2 to 9.0.1 without change.
9.0.final	01-Dec-2011	Duffy O'Craven	• Corrected name of Getting Started Guide and Updated to final revision
12.0.final	07-Aug-2012	Duffy O'Craven	• Updated Generating an EPICS, and made 12.0.final
14.0.final	17-Nov-2014	Duffy O'Craven	• Updated to 14.0.final without change.
15.0.01	25-Sep-2017	Lori Tribble	• Removed section 5.
15.0.final	25-Sep-2017	Lori Tribble	• Accepted all changes and marked as final
15.1.final	15-Feb-2018	Lori Tribble	• Updated version in preparation of release 15.1
15.2.final	31-Oct-2018	Lori Tribble	• Updated version in preparation of release 15.2
16.0.1	19-Aug-2019	Lori Tribble	• Updated version. Updated document to remove the Test Method, Conditionality, and Notes & Results sections. Added Test Directives directions.
20.0.1	03-May-2022	Emily Hayes	• Updated Introduction per BTLWG-312 • Updated version
23.0	08-Dec-2022	Emily Hayes	• Updated version to 23.0 without change
26.0.final	15-Nov-2024	Mike Osborne	• Removed VTS script information and Special Test Instruction references. • Update version to 26.0